

- comparator, 380  
compiled-code simulator, 102  
complementarity pivoting, 391, 392  
complementarity variable, 392  
complementary pivot method, 391  
complete multiple backtrace, 200  
completeness, 159  
component boundary, 451  
component level, 60  
compression, 513  
computed distortion, 376  
concurrent BIST, 530  
concurrent fault detection phase, 240  
concurrent fault simulator, 113, 238  
concurrent operation test, 298  
concurrent testing, 495  
conductance fault model, 446  
conducting path, 445  
cone segmentation, 500  
conflict, 162  
consistency procedure, 178  
constant electric-field scaling, 14  
Constructive Dilemma, 198  
CONT-2, 239  
contact test, 30  
contactor, 27  
contention circuit, 305  
contention test, 306  
CONTEST, 239  
CONTROL cell, 571  
control cell, 581  
control point, 529  
control-and-observe boundary scan cell, 565  
controllability, 129  
controllability iteration, 142  
controlling event, 423  
CONTROLR cell, 571  
convergence, 114  
converter gain, 323  
COP, 131  
core, 529, 605, 606  
core isolation, 591  
core-disconnect state, 585  
core-disconnect switch, 587  
core-test language, 607  
correlated delay defects, 435  
correlator, 343  
corrosion, 259, 260  
cosmic ray, 261  
cost, 36  
cost function, 240, 241, 402  
count function, 537  
coupled (victim) cell, 269, 270  
coupling (aggressor) cell, 269, 270  
coupling capacitance, 592  
coupling fault, 256, 258, 268  
CRC, 300, 514  
CREATOR, 116  
CRIS, 247  
critical area, 283  
critical data pattern, 84  
critical path, 418  
critical path length, 283  
critical path tracing, 125, 206  
critical resistance, 444  
critical timing path, 434  
cross-correlation, 343  
cross-point, 61  
cross-point fault, 61, 65  
crossover, 247  
Crouch, 624  
CSTP, 525  
CTL, 607  
cube intersection, 177  
current noise, 380  
current testing, 14, 440  
current transmission, 591  
current vector, 240  
CUT, 24, 495  
cutoff frequency, 381  
cutting algorithm, 130  
cycle breaking, 481  
cycle-free circuit test complexity, 227  
cycle-free circuits, 225  
cyclic redundancy check code, 514  
cyclic redundancy code, 300, 615  
cyclic redundancy code test, 300  
cyclic s-graph, 229  
  
D cell, 583  
D flip-flop, 212  
D-ALG, 176  
D-Algorithm, 176, 180  
D-chain, 180  
D-cube, 177  
D-drive, 178  
D-frontier, 163, 174  
D-intersection, 177, 181  
D/A converter, 322  
D1, 581  
D2, 581  
Dabral, 627  
DAC, 322  
DAC glitch area, 323, 352  
DAC settling time, 323  
DAG, 226, 427, 480  
Das Gupta, 483  
data flow graph, 148  
data generator, 530, 533  
data path synthesis rules SR1 and SR2, 148  
data polynomial, 616  
data retention fault, 258, 295  
data transfer test, 298  
Data1 cell, 581  
Data2 cell, 581  
David, 628  
Davis, 627  
dB, 325, 368  
DBM, 580  
dBm0, 368